

IGBT

TRENCHSTOP[™] IGBT3 Chip SIGC39T60E

Data Sheet

Industrial Power Control

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TRENCHSTOP[™] IGBT3 Chip

Features:

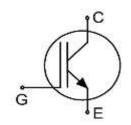
- 600V trench & field stop technology
- Low V_{CEsat}
- Low turn-off losses
- Short tail current
- Positive temperature coefficient
- Easy paralleling

Recommended for:

- Power modules
- Discrete components

Applications:

- Drives
- White goods
- Resonant applications



Chip Type	V _{CE}	I Cn	Die Size	Package
SIGC39T60E	600V	75A	6.59mm x 5.91mm	Sawn on foil

Mechanical Parameters

Die size		6.59 x 5.91		
Emitter pad size		See chip drawing	2	
Gate pad size		1.52 x 0.82	mm ²	
Area total		38.95		
Silicon thickness		70	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	686		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal	Backside metal Ni Ag – system To achieve a reliable solder connection it is stro recommended not to consume the Ni layer complete production process			
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500µm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
Storage environment (<6 months)	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 2	25°C	
	for open MBB bags	Acc. IEC 62258-3; Section 9.4 Storage Environ	ment.	



Maximum Ratings

In general, from reliability and lifetime point of view, the lower the operation junction temperature and/or the applied voltage, the greater the expected lifetime of any semiconductor device.

Parameter	Symbol	Value	Unit	
Collector-emitter voltage, T_{vj} =25°C	V _{CE}	600	V	
DC collector current, limited by $T_{vj max}$ ¹	I _C	-	А	
Pulsed collector current, t_p limited by $T_{vj max}^2$	I _{C,puls}	225	А	
Gate-emitter voltage	V_{GE}	±20	V	
Virtual junction temperature	T _{vj}	-40 +175	°C	
Short circuit data $^{1/2/3}$ V _{GE} =15V, V _{CC} =360V, T_{vj} =150°C	t _{sc}	6	μs	
Reverse bias safe operating area (RBSOA) ²	$I_{C,max} = 150A, V_{CEmax} = 600V, T_{vj} \le 150^{\circ}C$			

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Symbol Conditions	Conditions	Value			Unit
		Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	<i>V</i> _{GE} =0V, <i>I</i> _C =4mA	600	-	-	
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, <i>I</i> _C =75A	1.05	1.45	1.85	V
Gate-emitter threshold voltage	V _{GE(th)}	$I_{\rm C}$ =1.2mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =600V, V _{GE} =0V	-	-	3.8	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V, V _{GE} =20V	-	-	600	nA
Integrated gate resistor	r _G			none		Ω

Electrical Characteristics²

Parameter	Symbol	Conditions	Value			Unit
Falameter		Conditions	min.	typ.	max.	Unit
Input capacitance	C _{ies}	V _{CE} =25V, V _{GE} =0V, <i>f</i> =1MHz T _{vj} =25°C	-	4620	-	
Output capacitance	C _{oes}		-	288	-	pF
Reverse transfer capacitance	C _{res}		-	137	-	

¹ Depending on thermal properties of assembly.

² Not subject to production test - verified by design/characterization.

³ Allowed number of short circuits: <1000; time between short circuits: >1s.



Further Electrical Characteristics

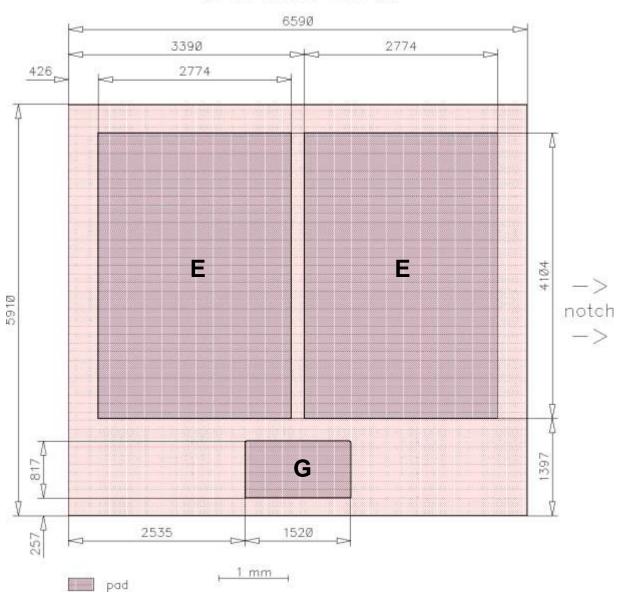
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	-	-
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L7571L, L7571T



Chip Drawing



Die-Size 6590 um x 5910 um

E = Emitter

 $\mathbf{G} = \text{Gate}$

L7571L, L7571T



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description

AQL 0.65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Revision	Subjects (major changes since last revision)	Date
2.1	Final data sheet	19.07.2017

Relevant Application Notes



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L7571L, L7571T

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